## **Dopants Dependent Microplasma Induced Surface Chemistries on P- and N-Doped Si-ncs**

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## Motivation

- Silicon nanocrystals (Si-ncs) carrier multiplications, abundance and non-toxicity are important for a next generation low cost and high efficiency PV fabrications.
- The doping of Si-ncs presents a unique scenario which in principle is enabling control of the energy band gap and the Fermi energy to yield both n- and p-doped nanocrystals.
- The position of the work function is playing the important role for band alignment in solar cells, which results in photocurrent collection efficiency with improved device performance.





Used to understanding the relative position of the Fermi level

a result  $H_2O_2$  is produced. (absence of OH absorption peak in FTIR)

CH<sub>3</sub>CH<sub>2</sub>O<sup>-</sup> may not be reacting with surface of n-Si-ncs then as

## Conclusions

- Efficient surfactant free microplasma surface engineering of doped Si-ncs.
- Enhanced PL quantum yield and stability in water for n-Si-ncs.
- Position of work function (Fermi level) can be tuned by surface engineering and doping.

This work was partially supported by NEDO project, the Royal Society International Exchange Scheme (IE120884), the Leverhulme International Network (IN-2012-136) and EPSRC (EP/K022237/1).